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SPACE CENTER



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UNDER THE MINISTRY OF SCIENCE, TECHNOLOGY AND INNOVATION

Small d-spacing WC/SiC multilayers for future hard x-ray telescope designs

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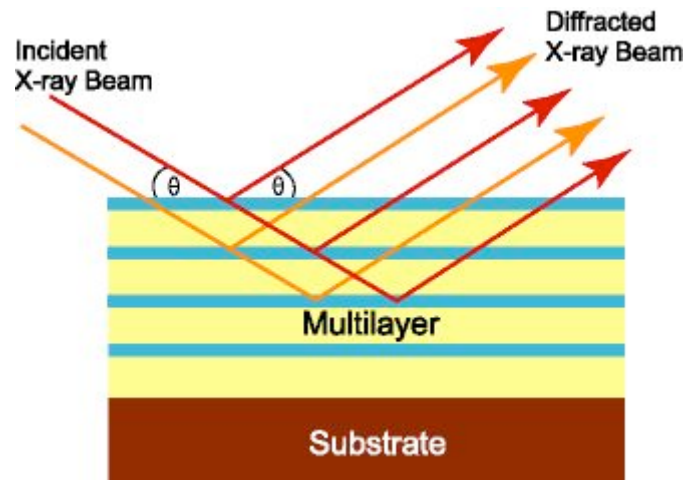


Outline

- **Reflectivity scans for WC/SiC**
- **Transverse scans WC/SiC**
- **Discuss optical constants for WC and SiC**
- **Telescopes up to 250 keV**



Multilayers



**Diffuse
interface**

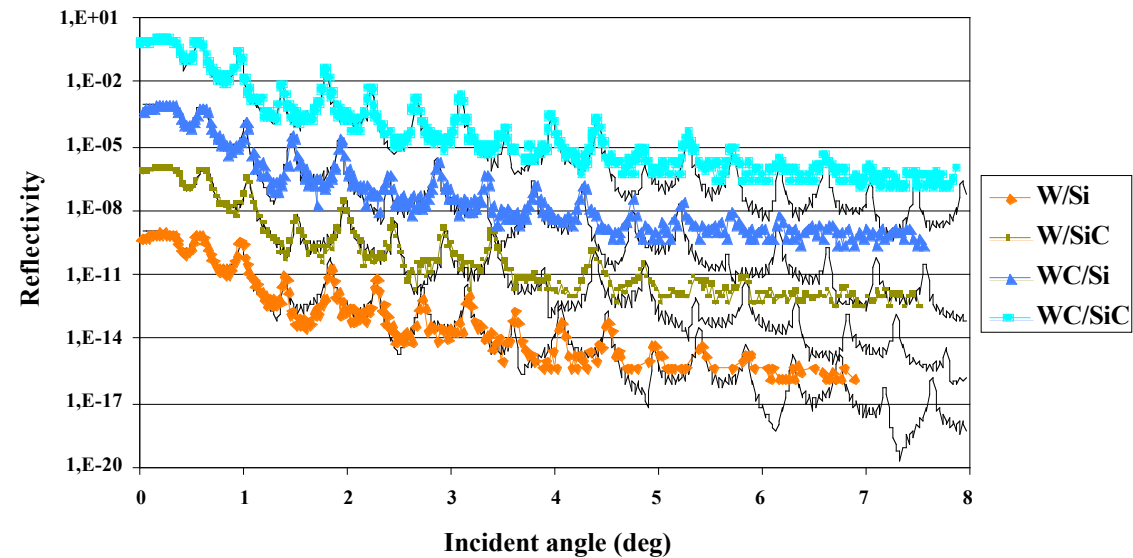


**Sharp rough
interface**





Reflectivity scan with d-spacings around 9.5 nm



	d-spacing (nm)	Γ	σ (nm)
W/Si	9.85	0.32	0.33
W/SiC	9.10	0.37	0.28
WC/Si	9.35	0.41	0.28
WC/SiC	10.05	0.37	0.23



Scatter

Distorted Wave Born Approximation

Roughness correlation:

$$\sigma = \sqrt{\sigma_d^2 + \sigma_r^2}$$

σ_r : real roughness
 σ_d : interfacial diffusion

$$\sigma_r = \sqrt{\sigma_{ucorr}^2 + \sigma_{corr}^2}$$

σ_{corr} : correlated roughness

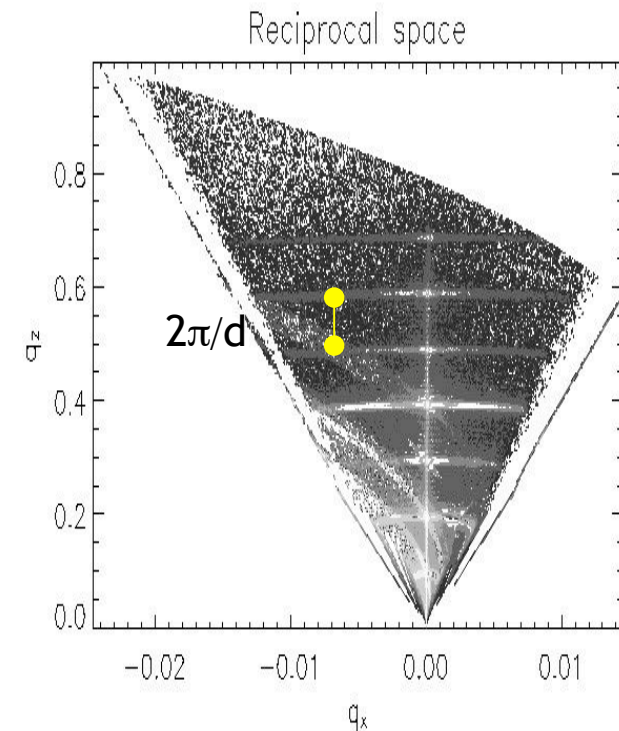
σ_{ucorr} : uncorrelated roughness ; $\sigma_{ucorr} \cong 0$

Self-affine surface (Sinha *et al*):

$$\langle h(r-R)h(r) \rangle = \sigma_{corr}^2 \exp \left\{ - \left(|R| / \xi \right)^{2/h} \right\}$$

h : fractal exponent $0 < h \leq 1$

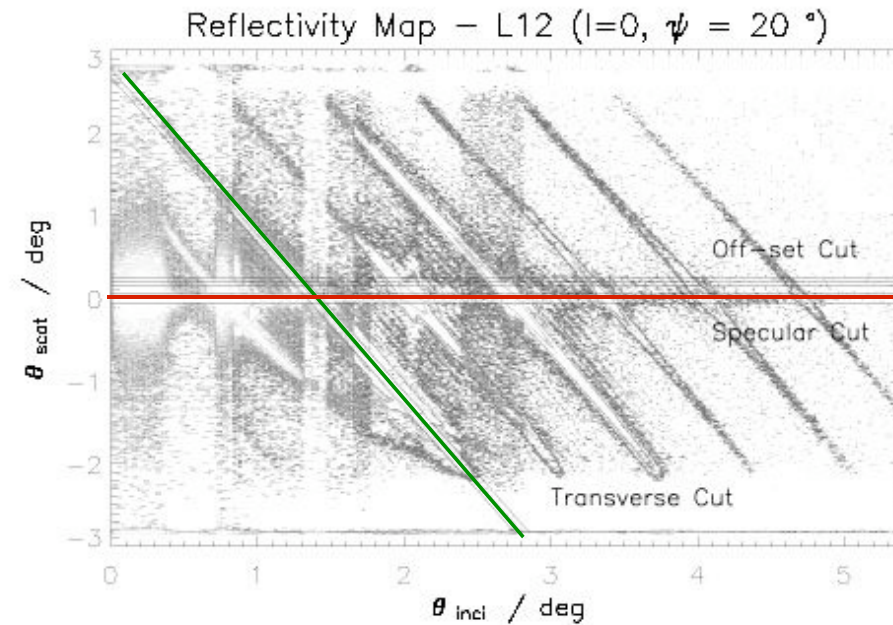
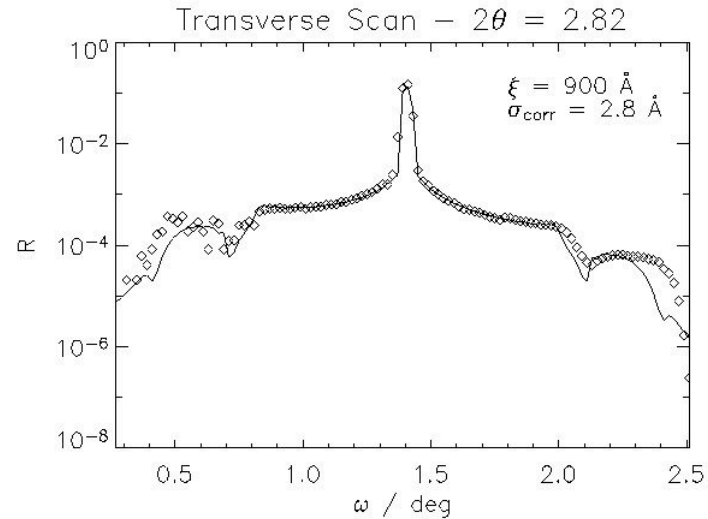
ξ : correlation length





Scan types

- 2D-map
- Specular scan
- Transverse scan

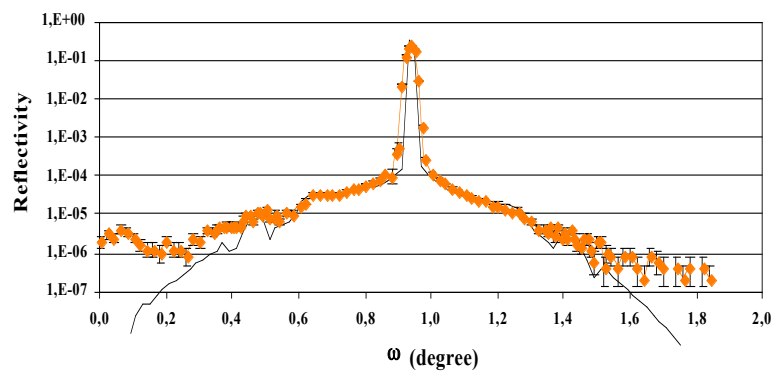




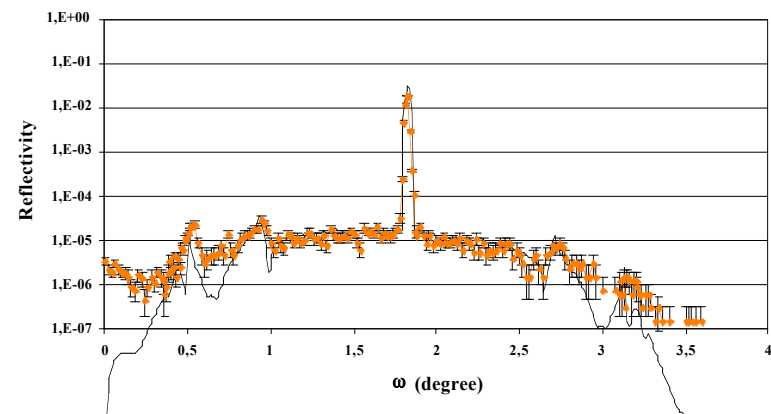
Transverse scans

Sample	θ (deg)	d (nm $\times 10$)	h ($\times 0.1$)	d_{corr} (nm $\times 0.01$)	d (nm $\times 0.03$)	$d_{\text{corr}}^2 + d^2$ (nm $\times 0.033$)
W/Si	3.6	20	0.25	0.25	0.20	0.32
W/SiC	3.9	10	0.20	0.15	0.25	0.29
WC/Si	3.9	10	0.15	0.12	0.20 - 0.25	0.23 - 0.28
WC/SiC	3.6	10	0.16	0.12	0.15	0.19

2. order peak for WC/SiC



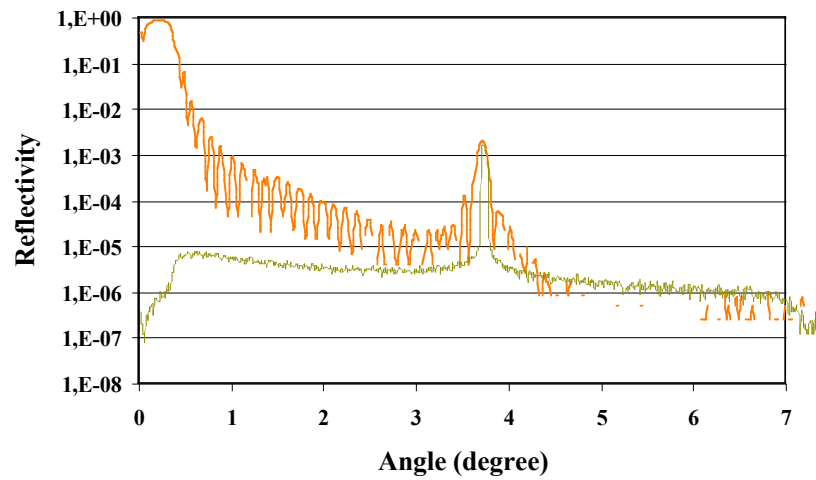
4. order peak for WC/SiC



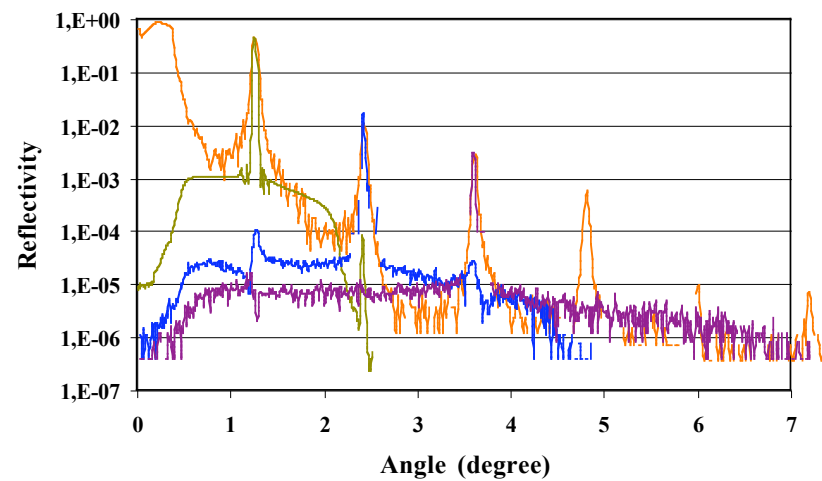


Specular and transverse scans

d-spacing 1.19 nm

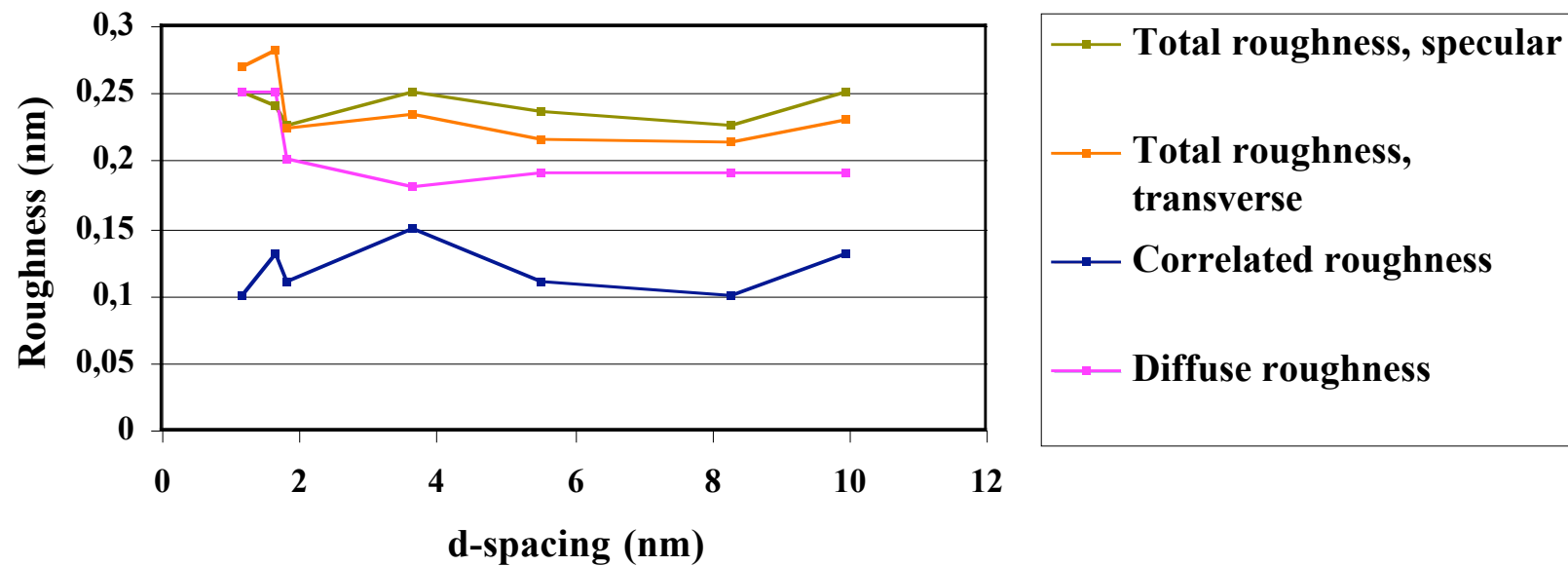


d-spacing 3,67 nm



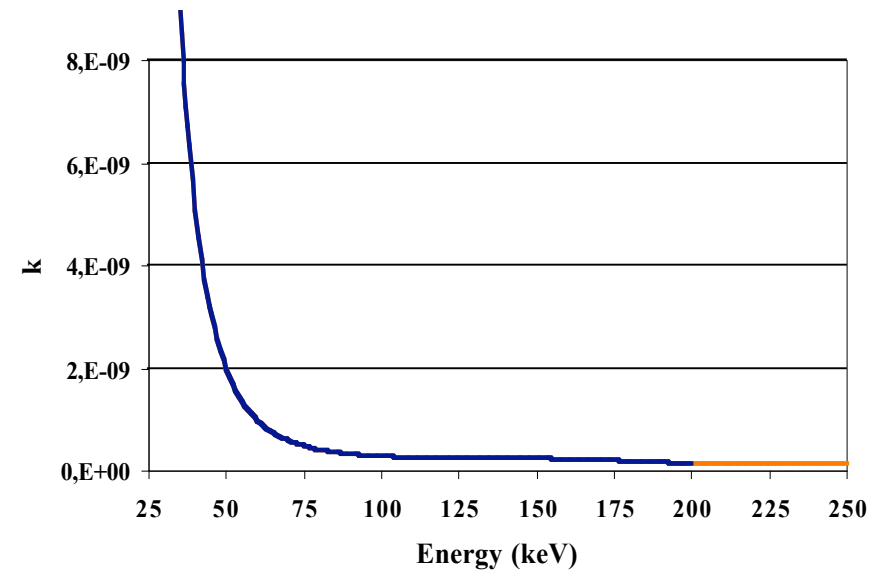
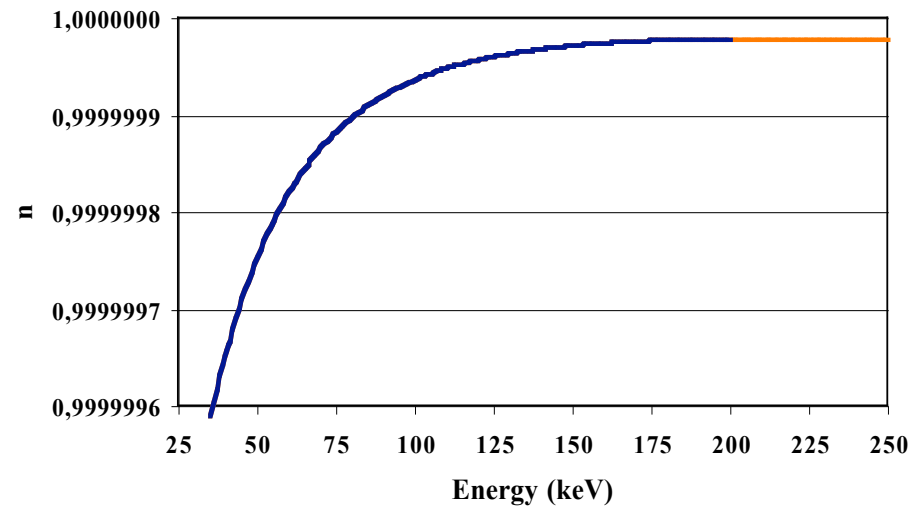


Roughness for WC/SiC multilayer





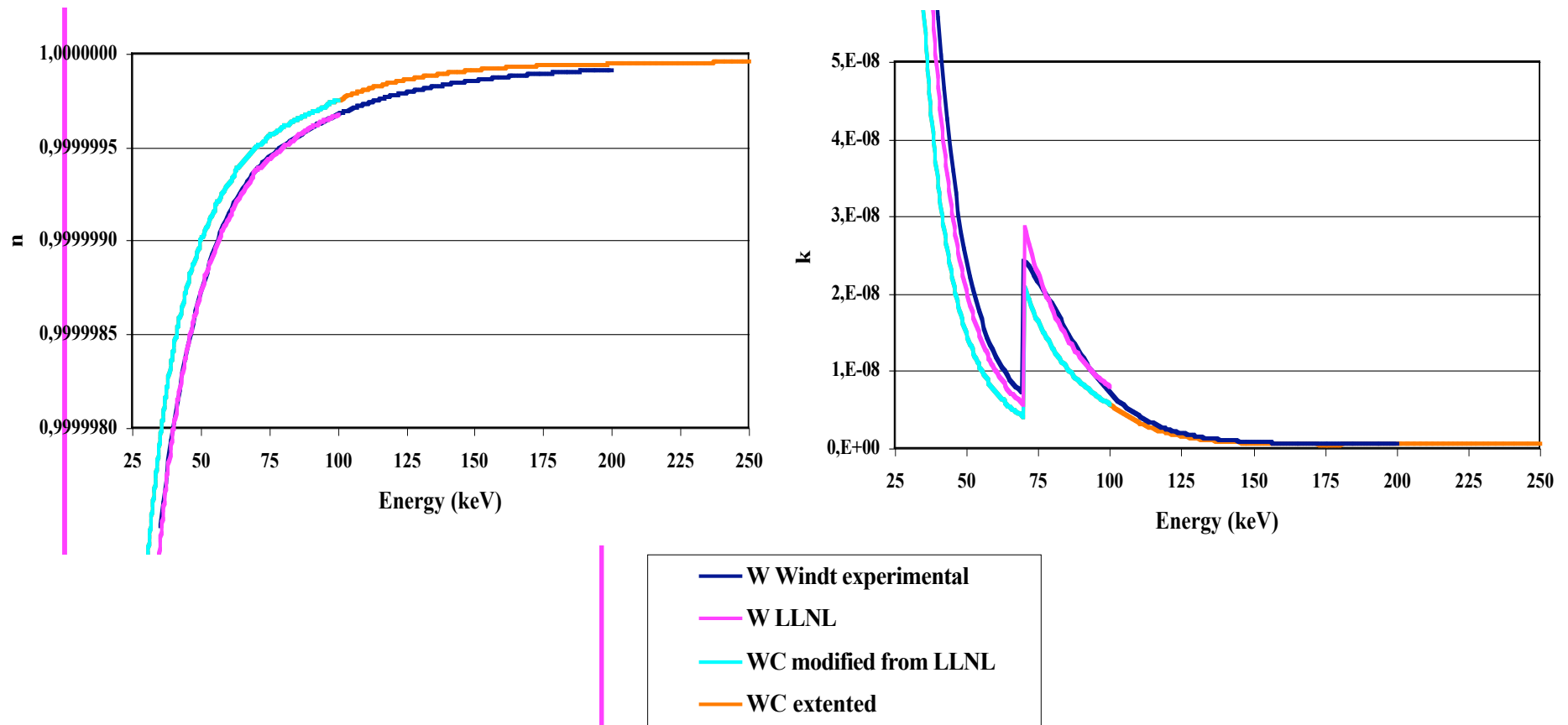
Optical constants SiC



— SiC Windt experimental
— SiC extented



Optical constants WC





Multilayer optimization

Power law thickness profiles:

$$D_i = \frac{a}{(b + i)^c}$$

- Constants a and b are uniquely determined by D_{\min} and D_{\max}
- For a given max and min graze angle for a group D_{\min} and D_{\max} are determined by the Bragg equation:

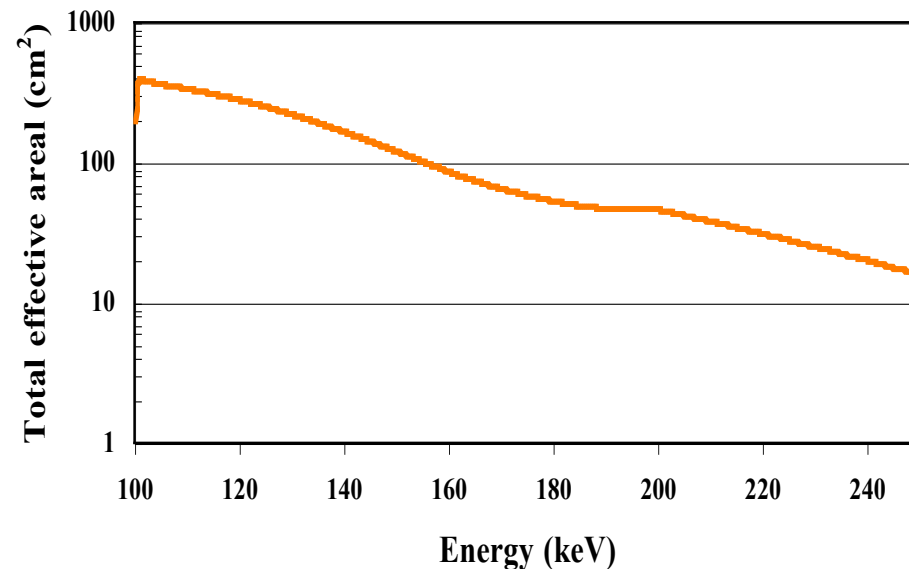
$$D = \frac{hc}{2E \sin \theta}$$

- Multilayer recipes are optimized over:
 - number of bilayers N
 - high Z fraction Γ
 - power law index c



Design based on a XEUS like configuration

Focal length	50 m
R	255-365 mm
Inci. angles	1.27 – 1.85 mrad
# shells	109
Shell thickness	0.2 mm
Primary mirror L	400 mm
Energy range	100 – 250 keV
Substrate	Si
Material combination	WC/SiC



D_{\min} range = 1.7nm – 1.4 nm

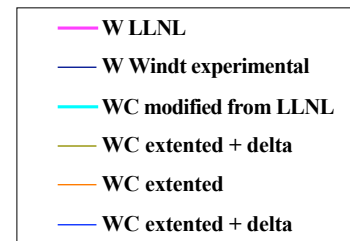
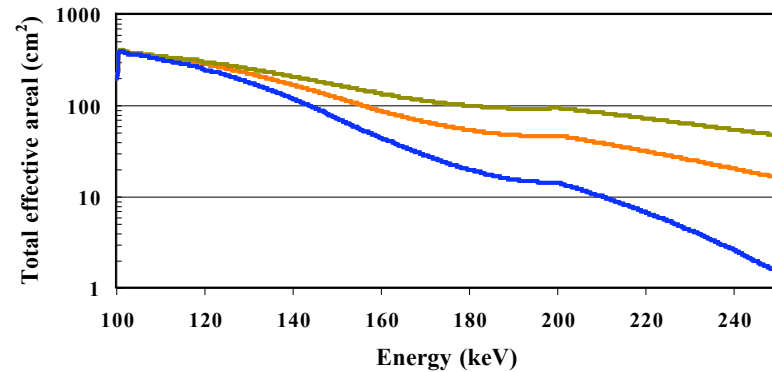
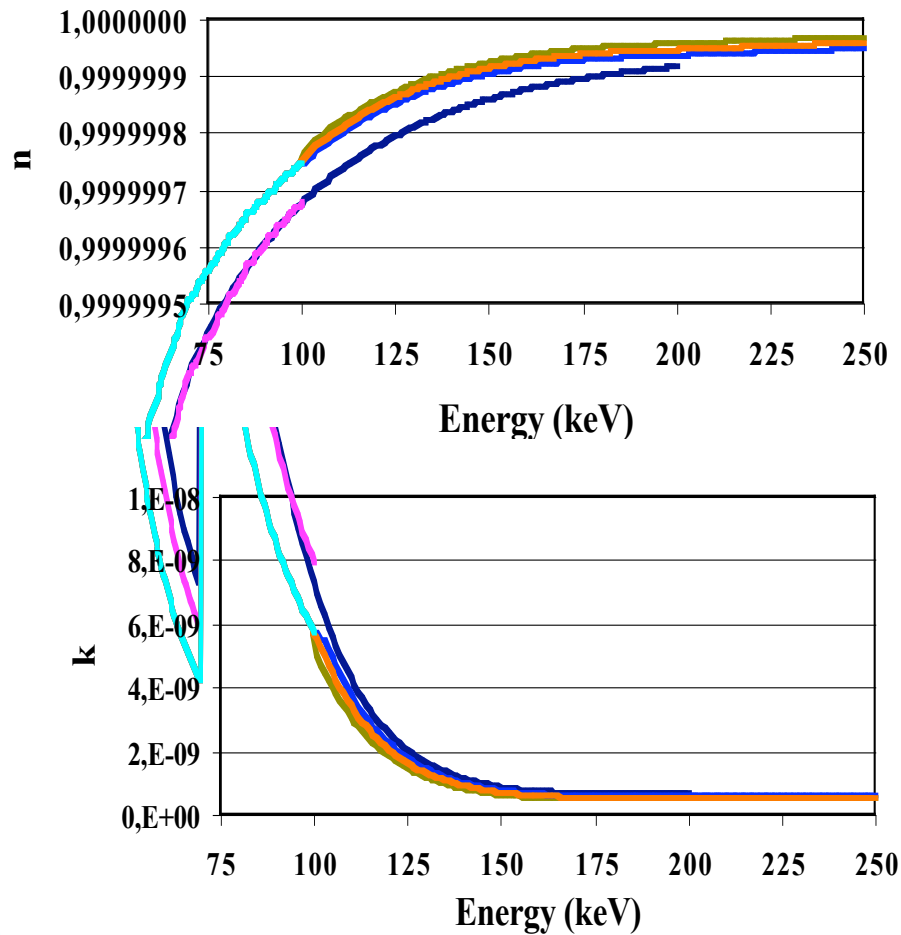
N = 1000 bilayers

Γ range = 0.43 – 0.44

C = 0.260- 0.390

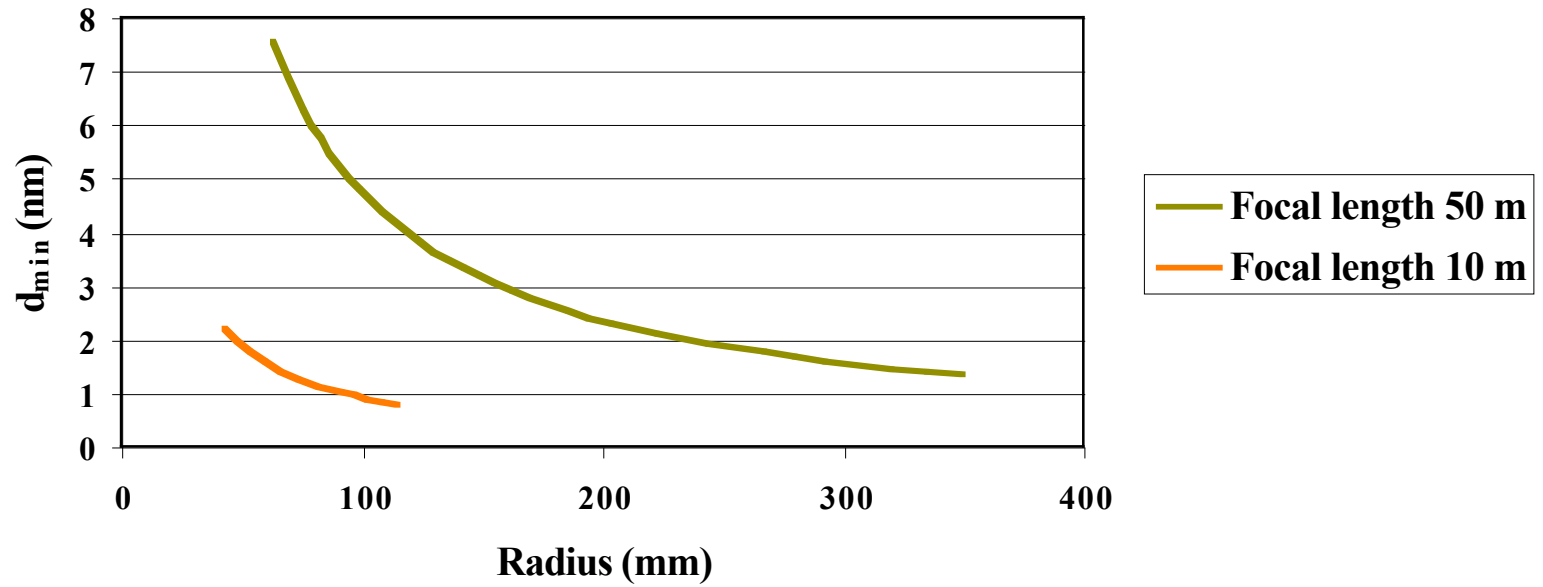


Optical constants for WC





D_{\min} for $E_{\max} = 250 \text{ keV}$





Summery

- **Demonstrated very thin WC/SiC multilayer**
- **Shown problems caused by unknown optical constants**
- **Thin coatings can be used for:**
 - **Large radius telescopes with long focal length**
 - **High energy telescopes with short focal length**
 - **Telescope looking at small band at high energy**



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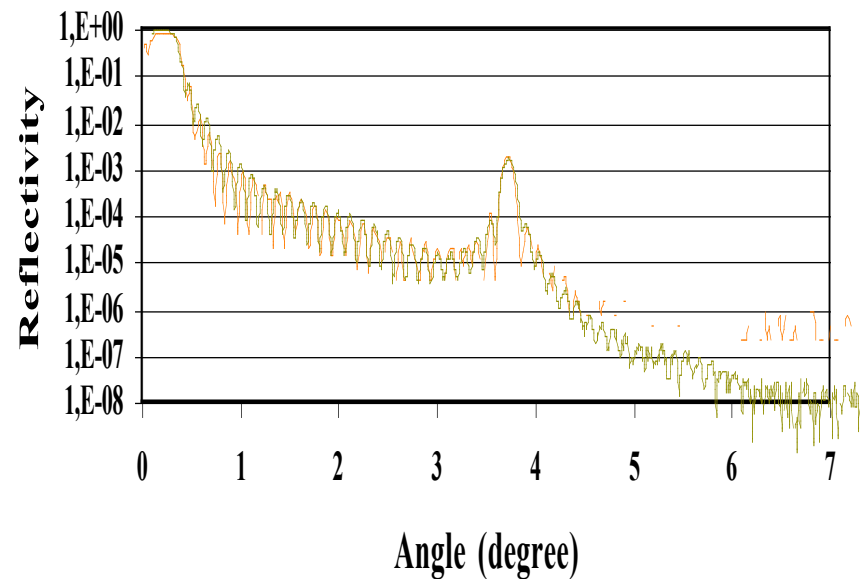
Hard x-ray focusing telescopes

	Launche	Energy max (keV)	Coatings	Focullength (m)
NuSTAR	2009	80	Pt/SiC W/SiC	9
Constalation-X	~2015	70		
XEUS	~2020	30		50
NEXT	~200?	80	Pt/SiC	

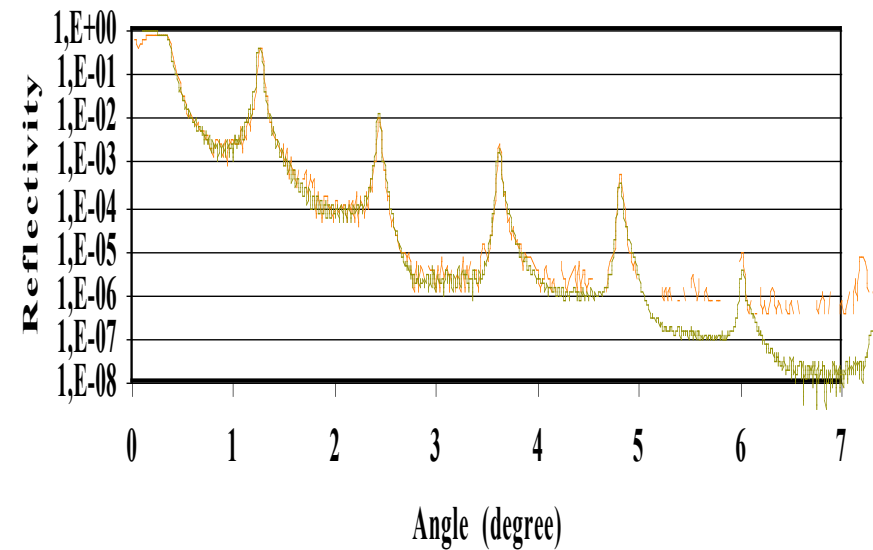


Stability of WC/SiC coating over time

d-spacing 1.19 nm



d-spacing 3,67 nm



— September 2000

— November 2004